10614997_CLSTITLES.txt Titles of Most Frequently Occurring Classifications of Patents Returned From A Search of 10614997 on November 03, 2005

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714/724
                     (1 OR, 6 XR)
                            ERROR DETECTION/CORRECTION AND FAULT
                    714 :
                             DETECTION/RECOVERY
           714/699
                           PULSE OR DATA ERROR HANDLING
           714/724
                           .Digital logic testing
     324/158.1
                    (4 OR, 2 XR)
324 : ELECTRICITY: MEASURING AND TESTING
           Class
           324/158.1
                          MISCELLANEOUS
     324/754
                     (4 OR, 2 XR)
                    324 : ELECTRICITY: MEASURING AND TESTING
           Class
           324/500
                          FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
.Of individual circuit component or element
           324/537
           324/754
                           ..With probe elements
                    (5 OR, 1 XR)
     324/765
                   324 : ELECTRICITY: MEASURING AND TESTING
           Class
           324/500
                           FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
.Of individual circuit component or element
           324/765
                           .. Test of semiconductor device
    714/733
                     (0 \text{ OR}, 6 \text{ XR})
           Class
                    714 : ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
                          PULSE OR DATA ERROR HANDLING
Digital logic testing
           714/699
           714/724
           714/733
                           ..Built-in testing circuit (BILBO)
                     (0 OR, 5 XR)
    209/573
                    209 : CLASSIFYING, SEPARATING, AND ASSORTING SOLIDS
           Class
           209/509
                          SORTING SPECIAL ITEMS, AND CERTAIN METHODS AND
                                 APPARATUS (E.G., POCKET TYPE AND LIGHT RESPONSIVE
SORTING.
                                 ETC.) FOR SORTING ANY ITEMS
           209/552
                           .Condition responsive means controls separating
                                means
           209/571
                           .. Electrical test sensing property of item
           209/573
                           ... Electrical component tested
                    (2 OR, 3 XR)
324 : ELECTRICITY: MEASURING AND TESTING
FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
     324/758
           Class
           324/500
                                 ELECTRIC COMPONENTS
           324/537
                           .Of individual circuit component or element
           324/754
                          ..With probe elements
                           ...Probe alignment or positioning
           324/758
                    (4 OR, 1 XR)
324 : ELECTRICITY: MEASURING AND TESTING
           Class
           324/500
                          FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                                ELECTRIC COMPONENTS
           324/537
                          .Of individual circuit component or element
           324/763
                          ..DUT including test circuit
 3 324/73.1
                     (0 \text{ OR}, 3 \text{ XR})
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10614997_CLSTITLES.txt
                  324 : ELECTRICITY: MEASURING AND TESTING
           324/73.1
                           PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
                    (1 OR, 2 XR)
365 : STATIC INFORMATION STORAGE AND RETRIEVAL
    365/201
           Class
           365/189.01
                           READ/WRITE CIRCUIT
           365/201
                            .Testing
                    (0 OR, 2 XR)
257 : ACTIVE
    257/E23.149
                           ACTIVE SOLID-STATE DEVICES
...Liquid at normal operating temperature of
           257/E23.139
                            device (EPO)
.Arrangements for conducting electric current
           257/E23.141
                                  within device in operation from one component to
another,
                                  interconnections, e.g., wires, lead frames (EPO)
           257/E23.142
                            .. Including external interconnections
                                 consisting of multilayer structure of conductive and insulating layers inseparably formed on semiconductor
body
                                 (EPO)
                            ...With adaptable interconnections (EPO)
           257/E23.146
           257/E23.149
                            ....Comprising fuses, i.e., connections having
                               their state changed from conductive to nonconductive
(EPO)
    324/760
                      (0 \text{ OR}, 2 \text{ XR})
                    324 : ELECTRICITY: MEASURING AND TESTING
           Class
           324/500
                           FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                           ELECTRIC COMPONENTS
.Of individual circuit component or element
           324/537
324/754
                            ..With probe elements
           324/760
                            ...With temperature control
                      (0 OR, 2 XR)
     414/416.01
                    414 : MATERIAL OR ARTICLE HANDLING
           Class
           414/403
                           DEVICE FOR EMPTYING PORTABLE RECEPTACLE
           414/416.01
                           .Nongravity type
     702/119
                      (2 OR, 0 XR)
                    702 :
           Class
                            DATA PROCESSING: MEASURING, CALIBRATING, OR
                              TESTING
           702/108
                           TESTING SYSTEM
           702/117
                           .of circuit
           702/119
                           ..Including program initialization (e.g., program loading) or code selection (e.g., program
creation)
    714/32
                      (1 \text{ OR}, 1 \text{ XR})
           Class
                            ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
           714/100
                           DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
           714/1
                           .Reliability and availability
           714/25
                           ...Fault locating (i.e., diagnosis or testing)
           714/32
                           ...Particular stimulus creation
    714/718
                      (1 OR, 1 XR)
           Class
                    714 : ERROR DETECTION/CORRECTION AND FAULT
                             DETECTION/RECOVERY
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	714/699 714/718		10614997_CLSTITLES.txt PULSE OR DATA ERROR HANDLING .Memory testing
2	714/719 Class 714/699 714/718 714/719	714	OR, 1 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY PULSE OR DATA ERROR HANDLING .Memory testingRead-in with read-out and compare
2	714/100 714/1 714/2	714	OR, 0 XR) : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING .Reliability and availabilityFault recovery
	714/3 714/5 714/8		<pre>By masking or reconfigurationOf memory or peripheral subsystemIsolating failed storage location (e.g., sector remapping)</pre>
2	716/4 Class 716/1 716/4	(0 ¢	DR, 2 XR) : DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK CIRCUIT DESIGN .Testing or evaluating